

# Takano WM-7SR

## Particle Measurement System

The advanced solution for particle measurement on  $\leq 200\text{mm}$  unpatterned wafers

### System Overview

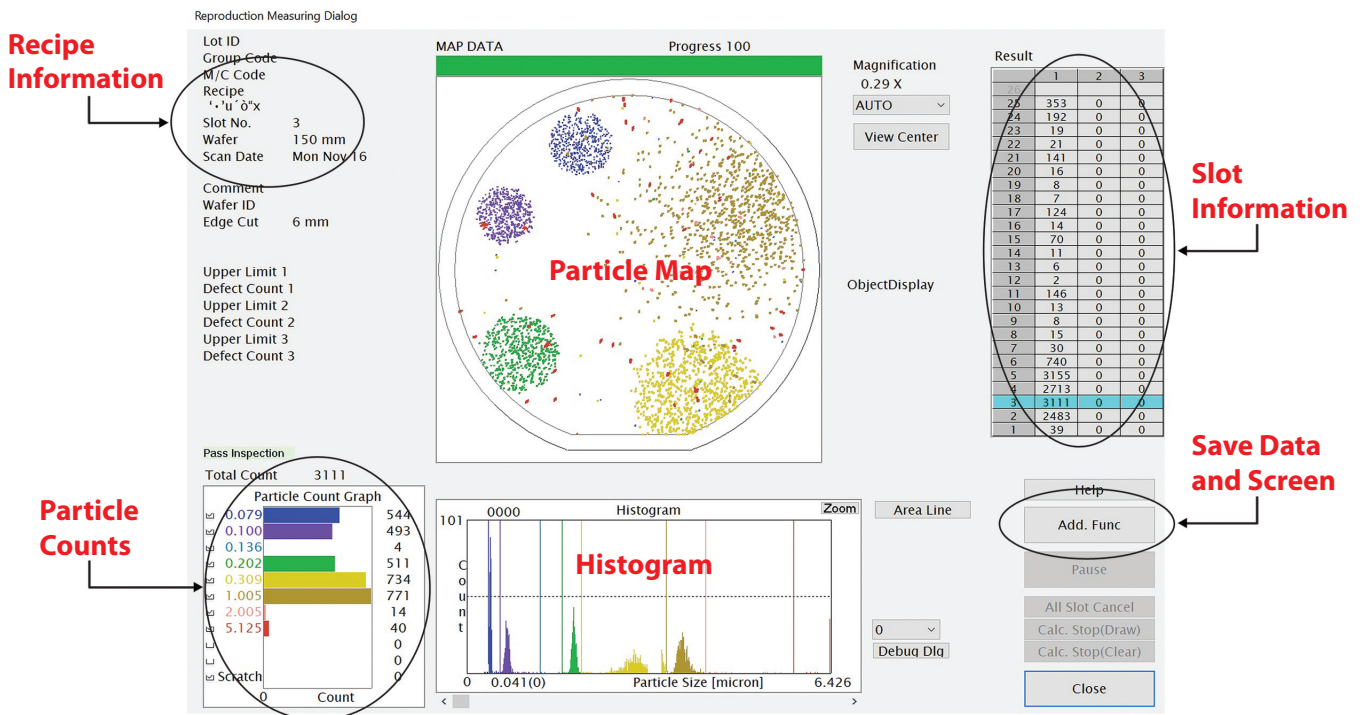
The Takano WM-7SR offers high-sensitivity particle measurements on non-patterned  $\leq 200\text{mm}$  wafers. Capable of measuring bare or filmed wafers, the WM-7SR system can deliver best-in-class 61nm detection sensitivity along with high throughput and excellent repeatability. The Takano WM-7SR is an advanced and cost-effective particle measurement solution – for today's requirements and for the future.



### Key Features & Benefits

- Advanced performance and superior cost-effectiveness
- 79nm particle detection sensitivity (Standard)
- 61nm particle detection sensitivity (Optional)
- 60 WPH throughput
- Windows 10 operating system
- 405nm laser diode at low incident angle
- Single open-cassette handler
- Full suite of options: Map Overlay, Haze Measurements, XY Coordinate Output, and much more
- Extensive OEM parts and service support, available long-term
- Quality-manufactured in Japan

## Measurement Results



## Measurement Specifications

- Maximum detection sensitivity: 0.079 $\mu$ m
- Dynamic range: 0.079–5 $\mu$ m
- Reproducibility of detection:  $\leq$ 1%
- Throughput: 60 WPH on 150mm wafers

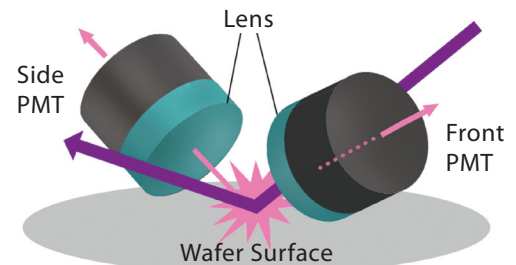
## Software/Hardware Options

- 61nm high-sensitivity mode
- Map overlay function
- X-Y coordinate output
- Auto-sensitivity correction
- Haze measurement
- SECS II communication
- Remote desktop
- HEPA-equipped Fan Filter Unit (FFU)
- Signal light tower
- Bare and filmed PSL calibration wafers

## Hardware Specifications

- Single open-cassette handler for 50–200mm wafers
- 405nm violet laser diode
- Windows 10 operating system
- PC: Intel Core-i7 6700 (3.4Ghz) processor, DDR3L 1600MHz 4GB RAM, 1TB SATA hard drive.
- 15" LCD monitor

## Low-Angle Incident Polarization, P or S



## Spiral Scanning

